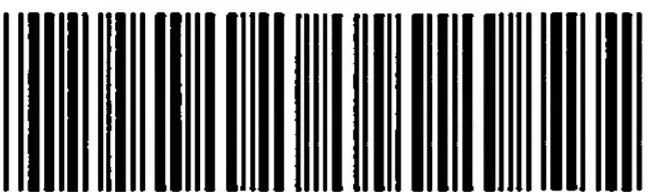


Search Notes



Application/Control No.

10/632.467

Examiner

Hiep T. Nguyen

**Applicant(s)/Patent under
Reexamination**

WATANABE ET AL.

Art Unit

2187

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)